



Tariffs

For external customers and internal customers with commercial financing

No p/p	Equipment	Access type ¹	Price ³ , RUB without VAT
1	Transmission electron microscope with probecorrector Titan Themis Z	per hour with AICF operator	15 523
2	Scanning electron microscope with low-vacuum mode Quattro S SEM	per hour with AICF operator	6 029
		per hour without AICF operator ²	4 029
		per day of training course	60 960
3	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	per hour with AICF operator	11 781
4	Dual beam scanning electron microscope Tescan Solaris	per hour with AICF operator	11 781
5	Pump probe transient absorption/reflection spectroscopy setup	per hour with AICF operator	4 300
6	Time-Correlated single photon spectroscopy setup	per hour with AICF operator	3 300
7	Femtosecond double pulse microcavity dispersion imaging optical setup	per hour with AICF operator	8 300
8	Compact low-temperature electro-optical imaging setup	per hour with AICF operator	3 800

Typical services provided by AICF

No p/p	Typical services	Used equipment	Unit of measurement, sample	Price ⁴ , RUB without VAT
1	Particle morphology investigation	Scanning electron microscope with low-vacuum mode Quattro S SEM	1 sample	8 029
2	Surface morphology investigation of the sample, if necessary, the use of a backscattered electron detector	Scanning electron microscope with low-vacuum	1 sample	11 043

		mode Quattro S SEM		
3	Investigation of the elemental composition of the sample (by 5 points)	Scanning electron microscope with low-vacuum mode Quattro S SEM	1 sample	8 029
4	Investigation of the elemental composition of the sample (mapping of 3 areas)	Scanning electron microscope with low-vacuum mode Quattro S SEM	1 sample	14 058
5	Particle morphology investigation	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	13 881
6	Surface morphology investigation of the sample, if necessary, the use of a backscattered electron detector	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	19 671
7	Investigation of the elemental composition of the sample (by 5 points)	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	21 671
8	Investigation of the elemental composition of the sample (mapping of 3 areas)	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	39 343
9	Preparation and visualization of cross-section	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	21 671
10	Preparation of lamella for TEM investigation	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	53 014
11	Preparation of lamella for TEM investigation at the given point in accordance with Customer request	Dual beam scanning electron	1 sample	64 795

		microscope Helios G4 UXe PFIB/SEM		
12	Investigation of multilayer structures in the STEM mode, including investigation of the elemental composition of the sample (along the line)	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	39 343
13	Investigation of the crystallographic orientation of the grain structure (EBSD)	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	1 sample	Договорная, зависит от ТЗ
14	Investigation of the morphology of nanoparticles in TEM or STEM modes	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	19 523
15	Investigation of the grain structure of a sample including determination of dislocation density	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	39 046
16	Investigation of the crystal structure of a sample using electron diffraction	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	58 569
17	Visualization of the crystal structure of the sample in high resolution TEM or STEM	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	39 046
18	Solution of the crystal structure of a sample using electron diffraction tomography	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	154 184
19	Investigation of the elemental composition of the sample using energy dispersive X-ray spectroscopy (EDX) (mapping of 3 areas)	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	35 046
20	Mapping of the elemental composition of the sample	Transmission	1 sample	50 569

	using energy dispersive x-ray spectroscopy (EDX) with atomic resolution (mapping of 3 areas)	electron microscope with probecorrector Titan Themis Z		
21	Investigation of the elemental composition of the sample, including light elements, using electron energy loss spectroscopy (EELS) (spectra acquisition at 5 points)	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	39 046
22	Mapping of the elemental composition of the sample, including light elements, using electron energy loss spectroscopy (EELS) in the STEM mode (mapping of 3 areas)	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	54 569
23	Visualization of nanoparticles using electron tomography	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	154 184
24	Visualization of multilayer structures (heterostructures) with atomic resolution	Transmission electron microscope with probecorrector Titan Themis Z	1 sample	54 569
25	IR spectrum measurement spectra acquisition at 5 points	IR microscope Bruker Lumos	1 sample	5 900

For internal customers⁵

No p/p	Equipment	Access type ¹	Price, RUB without VAT
1	Transmission electron microscope with probecorrector Titan Themis Z	per hour with AICF operator	4 103
		per hour without AICF operator ²	3 103
2	Scanning electron microscope with low-vacuum mode Quattro S SEM	per hour with AICF operator	1 597
		per hour without AICF operator ²	597
		per day of training course	4 777
3	Dual beam scanning electron microscope Helios G4 UXe PFIB/SEM	per hour with AICF operator	2 971
		per hour without AICF operator ²	1 971
4	Dual beam scanning electron microscope Tescan Solaris	per hour with AICF operator	2 971
		per hour without AICF operator ²	1 971
5	Pump probe transient absorption/reflection spectroscopy setup	per hour with AICF operator	2 300
6	Time-Correlated single photon spectroscopy setup	per hour with AICF operator	1 300
7	Femtosecond double pulse microcavity dispersion imaging optical setup	per hour with AICF operator	6 300

8	Compact low-temperature electro-optical imaging setup	per hour with AICF operator	1 800
9	IR microscope Bruker Lumos	per hour with AICF operator	1 597

Prices are indicated for equipment rent only; interpretation of results and preparation of reports are charged separately.

Duration and contents of the training are determined based on the trainee's level.

¹ Access to sample preparation equipment (except listed above) is not charged (free). However, in case operator assistance is required, a rate of 2 300 RUB / hour will be applied

² Access granted only after completing a corresponding training course

³ Internal customers with external (commercial financing), as well as participants of the Skolkovo project, are provided with an additional discount of 20% of the specified tariff. Services rendered with the help of Titan Themis Z equipment to the Skolkovo project participants are calculated at an individual rate (upon request)

*** The cost is indicated without taking into account the sample preparation

**** Including research projects of Skoltech employees, which are funded from a grant from the Skolkovo Foundation, grants from the Russian Science Foundation, RFBR, Ministry of Education and Science, Skoltech startups. The tariff is applied subject to the provision of supporting documents, otherwise the tariff "For external clients and internal clients with commercial financing" is applied